E·XFL



Welcome to E-XFL.COM

Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	768
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	12000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx08-pl84i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Routing Resources

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called *FastConnect* and *DirectConnect*, which enable extremely fast and predictable interconnection of modules within clusters and SuperClusters (Figure 1-5 and Figure 1-6). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance.

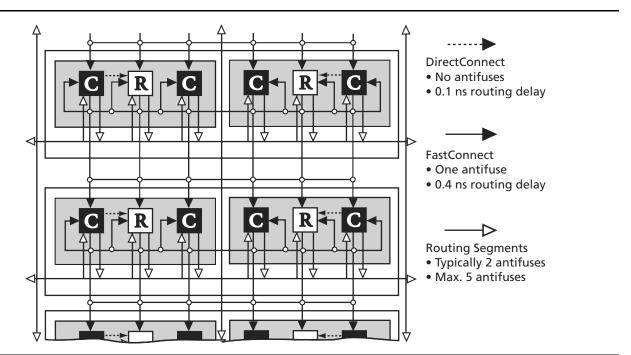


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

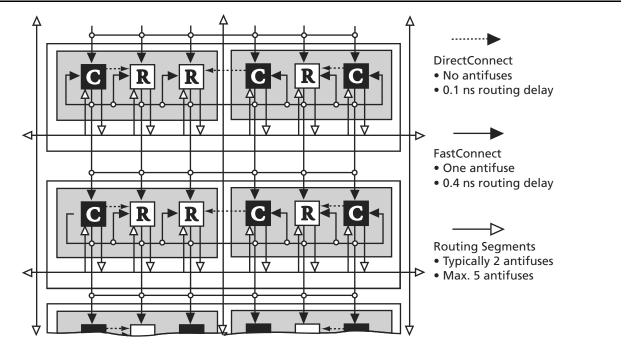


Figure 1-6 • **DirectConnect and FastConnect for Type 2 SuperClusters**

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 k Ω . TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 •	Boundary Scan Pin Functionality
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Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)				
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.				
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 $k\Omega$ on TMS.				

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Figure 1-7 • Device Selection Wizard

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero[®] Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify[®] for Actel from Synplicity[®], ViewDraw[®] for Actel from Mentor Graphics[®], ModelSim[®] HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD[™], and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys[®], and Cadence[®] Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

A54SX16P AC Specifications for (PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units	
I _{OH(AC)}	Switching Current High	$0 < V_{OUT} \le 1.4^{1}$	-44		mA	
		$1.4 \le V_{OUT} < 2.4^{1, 2}$	-44 + (V _{OUT} - 1.4)/0.024		mA	
		$3.1 < V_{OUT} < V_{CC}^{1, 3}$		EQ 1-1 on page 1-11		
	(Test Point)	$V_{OUT} = 3.1^{3}$		-142	mA	
I _{OL(AC)}	Switching Current High	$V_{OUT} \ge 2.2^{1}$	95		mA	
		$2.2 > V_{OUT} > 0.55^{1}$	V _{OUT} /0.023			
		$0.71 > V_{OUT} > 0^{1, 3}$		EQ 1-2 on page 1-11	mA	
	(Test Point)	$V_{OUT} = 0.71^{3}$		206	mA	
I _{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	-25 + (V _{IN} + 1)/0.015		mA	
slew _R	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns	
slew _F	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns	

Table 1-7 A54SX16P AC Specifications for (PCI Operation)

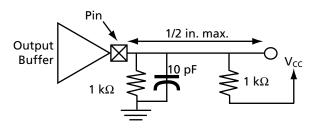
Notes:

1. Refer to the V/I curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.

2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.

3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.

4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



A54SX16P DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V _{CCA}	Supply Voltage for Array		3.0	3.6	V
V _{CCR}	Supply Voltage required for Internal Biasing		3.0	3.6	V
V _{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		0.5V _{CC}	$V_{CC} + 0.5$	V
V _{IL}	Input Low Voltage		-0.5	0.3V _{CC}	V
I _{IPU}	Input Pull-up Voltage ¹		0.7V _{CC}		V
IIL	Input Leakage Current ²	$0 < V_{IN} < V_{CC}$		±10	μA
V _{OH}	Output High Voltage	I _{OUT} = –500 μA	0.9V _{CC}		V
V _{OL}	Output Low Voltage	I _{OUT} = 1500 μA		0.1V _{CC}	V
C _{IN}	Input Pin Capacitance ³			10	pF
C _{CLK}	CLK Pin Capacitance		5	12	pF
C _{IDSEL}	IDSEL Pin Capacitance ⁴			8	pF

Table 1-8 • A54SX16P DC Specifications (3.3 V PCI Operation)

Notes:

1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Applications sensitive to static power utilization should assure that the input buffer is conducting minimum current at this input voltage.

2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.

3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

A54SX16P AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
	Switching Current High	$0 < V_{OUT} \le 0.3 V_{CC}^{1}$			mA
1		$0.3V_{CC} \le V_{OUT} < 0.9V_{CC}^{-1}$	-12V _{CC}		mA
IOH(AC)		$0.7V_{CC} < V_{OUT} < V_{CC}^{1, 2}$	–17.1 + (V _{CC} – V _{OUT})	EQ 1-3 on page 1-14	
	(Test Point)	$V_{OUT} = 0.7 V_{CC}^2$		-32V _{CC}	mA
	Switching Current High	$V_{CC} > V_{OUT} \ge 0.6 V_{CC}^{1}$			mA
1		$0.6V_{CC} > V_{OUT} > 0.1V_{CC}^{1}$	16V _{CC}		mA
I _{OL(AC)}		$0.18V_{CC} > V_{OUT} > 0^{1, 2}$	26.7V _{OUT}	EQ 1-4 on page 1-14	mA
	(Test Point)	$V_{OUT} = 0.18 V_{CC}^2$		38V _{CC}	
I _{CL}	Low Clamp Current	$-3 < V_{IN} \le -1$	-25 + (V _{IN} + 1)/0.015		mA
I _{CH}	High Clamp Current	$-3 < V_{IN} \le -1$	25 + (V _{IN} – V _{OUT} – 1)/0.015		mA
slew _R	Output Rise Slew Rate ³	$0.2V_{CC}$ to $0.6V_{CC}$ load	1	4	V/ns
slew _F	Output Fall Slew Rate ³	$0.6V_{CC}$ to $0.2V_{CC}$ load	1	4	V/ns

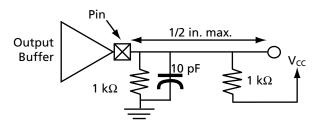
Table 1-9 • A54SX16P AC Specifications (3.3 V PCI Operation)

Notes:

1. Refer to the V/I curves in Figure 1-10 on page 1-14. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST# which are system outputs. "Switching Current High" specification are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD# which are open drain outputs.

2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 1-10 on page 1-14. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.

3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



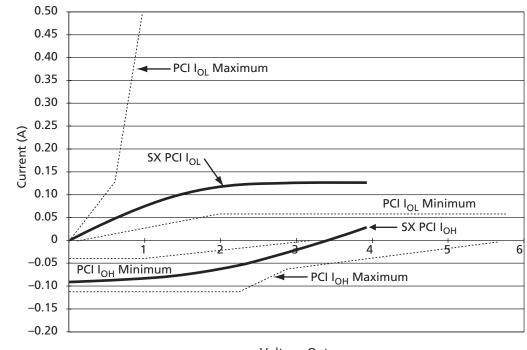


Figure 1-10 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

Voltage Out

Figure 1-10 • 3.3 V PCI Curve for A54SX16P Device

 $I_{OH} = (98.0/V_{CC}) \times (V_{OUT} - V_{CC}) \times (V_{OUT} + 0.4V_{CC})$ for V_{CC} > V_{OUT} > 0.7 V_{CC} $I_{OL} = (256/V_{CC}) \times V_{OUT} \times (V_{CC} - V_{OUT})$ for 0 V < V_{OUT} < 0.18 V_{CC}

EQ 1-3

EQ 1-4

Evaluating Power in SX Devices

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

You should complete a power evaluation early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

- 1. Estimate the power consumption of the application.
- 2. Calculate the maximum power allowed for the device and package.
- 3. Compare the estimated power and maximum power values.

Estimating Power Consumption

The total power dissipation for the SX family is the sum of the DC power dissipation and the AC power dissipation. Use EQ 1-5 to calculate the estimated power consumption of your application.

$$P_{Total} = P_{DC} + P_{AC}$$

р

х

у

r₁

fn

fp

f_{s1}

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. The Standby power is shown in Table 1-12 for commercial, worst-case conditions (70°C).

Table 1-12	• Sta	ndby Pov	ver
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I _{cc}	V _{cc}	Power		
4 mA	3.6 V	14.4 mW		

The DC power dissipation is defined in EO 1-6.

 $P_{DC} = (I_{standby}) \times V_{CCA} + (I_{standby}) \times V_{CCR} +$ $(I_{standbv}) \times V_{CCI} + xV_{OL} \times I_{OL} + y(V_{CCI} - V_{OH}) \times V_{OH}$

EQ 1-6

AC Power Dissipation

The power dissipation of the SX Family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined in EQ 1-7 and EQ 1-8.

EQ 1-7

 $P_{AC} = V_{CCA}^2 \times [(m \times C_{EOM} \times f_m)_{Module} +$ $(n \times C_{EOI} \times f_n)_{Input Buffer} + (p \times (C_{EOO} + C_L) \times f_p)_{Output Buffer} +$ $(0.5 \times (q_1 \times C_{EQCR} \times f_{q1}) + (r_1 \times f_{q1}))_{RCLKA} +$ $(0.5 \times (q2 \times CEQCR \times f_{q2}) + (r2 \times f_{q2}))RCLKB +$ $(0.5 \times (s_1 \times C_{EOHV} \times f_{s1}) + (C_{EOHF} \times f_{s1}))_{HCLK}]$

EQ 1-8

Definition of Terms Used in Formula

m	=	Number of logic modules switching at f _m
n	=	Number of input buffers switching at f _p

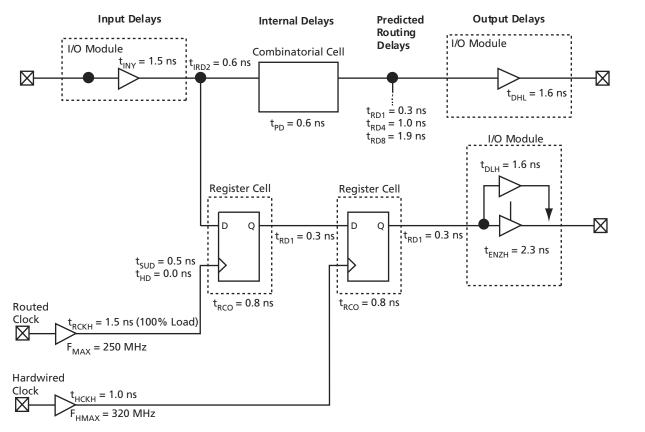
- = Number of input buffers switching at f_n
- Number of output buffers switching at fp =
- Number of clock loads on the first routed array q_1 clock
- Number of clock loads on the second routed array = q_2 clock
 - = Number of I/Os at logic low
 - Number of I/Os at logic high =
 - = Fixed capacitance due to first routed array clock
- Fixed capacitance due to second routed array = r₂ clock
- Number of clock loads on the dedicated array = s₁ clock

$$C_{EQM}$$
 = Equivalent capacitance of logic modules in pF

- Equivalent capacitance of input buffers in pF C_{EQI} =
- Equivalent capacitance of output buffers in pF $C_{EOO} =$
- Equivalent capacitance of routed array clock in pF $C_{EOCR} =$
- Variable capacitance of dedicated array clock $C_{EOHV} =$
- Fixed capacitance of dedicated array clock $C_{EOHF} =$
- C = Output lead capacitance in pF
- Average logic module switching rate in MHz fm =
 - = Average input buffer switching rate in MHz
 - = Average output buffer switching rate in MHz
- = Average first routed array clock rate in MHz f_{q1}
- Average second routed array clock rate in MHz f_{q2} =
 - = Average dedicated array clock rate in MHz



SX Timing Model



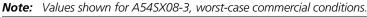


Figure 1-12 • SX Timing Model

Hardwired Clock

External Setup = $t_{INY} + t_{IRD1} + t_{SUD} - t_{HCKH}$ = 1.5 + 0.3 + 0.5 - 1.0 = 1.3 ns

Clock-to-Out (Pin-to-Pin)

$$= t_{HCKH} + t_{RCO} + t_{RD1} + t_{DHL}$$

= 1.0 + 0.8 + 0.3 + 1.6 = 3.7 r

EQ 1-16

Routed Clock

	External Setup = $t_{INY} + t_{IRD1} + t_{SUD} - t_{RCKH}$ = 1.5 + 0.3 + 0.5 - 1.5 = 0.8 ns	
EQ 1-15		EQ 1-17
	Clock-to-Out (Pin-to-Pin)	
	$= t_{RCKH} + t_{RCO} + t_{RD1} + t_{DHL}$	
	= 1.52+ 0.8 + 0.3 + 1.6 = 4.2 ns	
EO 1-16		EQ 1-18



Table 1-17 A54SX08 Timing Characteristics (Continued)

(Worst-Case Commercial Conditions,	V _{CCR} = 4.75 V, V _{CC}	_{A,} V _{CCI} = 3.0 V, T _J = 70°C)
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		'-3' \$	Speed	'-2' \$	5peed	'-1' \$	5peed	'Std' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)		1.0		1.1		1.3		1.5	ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)		1.0		1.2		1.4		1.6	ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew		0.1		0.2		0.2		0.2	ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Arra	ay Clock Networks									
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)		1.3		1.5		1.7		2.0	ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell Input)		1.4		1.6		1.8		2.1	ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)		1.4		1.7		1.9		2.2	ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)		1.5		1.7		2.0		2.3	ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)		1.5		1.7		1.9		2.2	ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)		1.5		1.8		2.0		2.3	ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)		0.1		0.2		0.2		0.2	ns
t _{RCKSW}	Maximum Skew (50% load)		0.3		0.3		0.4		0.4	ns
t _{RCKSW}	Maximum Skew (100% load)		0.3		0.3		0.4		0.4	ns
TTL Output	Module Timing1									
t _{DLH}	Data-to-Pad LOW to HIGH		1.6		1.9		2.1		2.5	ns
t _{DHL}	Data-to-Pad HIGH to LOW		1.6		1.9		2.1		2.5	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.8		3.2	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.1		3.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z		1.4		1.7		1.9		2.2	ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

Table 1-18 A54SX16 Timing Characteristics (Continued)

(Worst-Case Commercial Conditions, V	/ _{CCR} = 4.75 V, V _{CC}	_{CA} ,V _{CCI} = 3.0 V, T _J = 70°C)
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		'-3' !	Speed	'-2' :	Speed	'-1' :	Speed	'Std'	Speed	
Parameter	Description		Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Network									
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)		1.2		1.4		1.5		1.8	ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)		1.2		1.4		1.6		1.9	ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew		0.2		0.2		0.3		0.3	ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Arra	ay Clock Networks									
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)		1.6		1.8		2.1		2.5	ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)		1.8		2.0		2.3		2.7	ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)		1.8		2.1		2.5		2.8	ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)		2.0		2.2		2.5		3.0	ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)		1.8		2.1		2.4		2.8	ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)		2.0		2.2		2.5		3.0	ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)		0.5		0.5		0.5		0.7	ns
t _{RCKSW}	Maximum Skew (50% load)		0.5		0.6		0.7		0.8	ns
t _{RCKSW}	Maximum Skew (100% load)		0.5		0.6		0.7		0.8	ns
TTL Output	Module Timing ³									
t _{DLH}	Data-to-Pad LOW to HIGH		1.6		1.9		2.1		2.5	ns
t _{DHL}	Data-to-Pad HIGH to LOW		1.6		1.9		2.1		2.5	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.8		3.2	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.1		3.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z		1.4		1.7		1.9		2.2	ns
t _{ENHZ}	Enable-to-Pad, H to Z		1.3		1.5		1.7		2.0	ns

Notes:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} , the loading is 5 pF.

A54SX16P Timing Characteristics

Table 1-19 • A54SX16P Timing Characteristics

(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA}, V_{CCI} = 3.0 V, T_J = 70°C)

		'-3' 9	5peed	'-2' \$	5peed	'-1' :	5peed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
C-Cell Propa	agation Delays ¹									
t _{PD}	Internal Array Module		0.6		0.7		0.8		0.9	ns
Predicted R	outing Delays ²									
t _{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t _{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.4		0.4		0.5	ns
t _{RD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t _{RD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t _{RD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t _{RD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t _{RD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t _{RD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns
R-Cell Timir	ng									
t _{RCO}	Sequential Clock-to-Q		0.9		1.1		1.3		1.4	ns
t _{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.7		0.8	ns
t _{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.9		1.0	ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Modu	le Propagation Delays									
t _{INYH}	Input Data Pad-to-Y HIGH		1.5		1.7		1.9		2.2	ns
t _{INYL}	Input Data Pad-to-Y LOW		1.5		1.7		1.9		2.2	ns
Predicted Ir	put Routing Delays ²									
t _{IRD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t _{IRD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t _{IRD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t _{IRD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t _{IRD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t _{IRD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Delays based on 10 pF loading.

Table 1-19 • A54SX16P Timing Characteristics (Continued)

(Worst-Case Commercial Conditions	, V _{CCR} = 4.75 V, V _C	_{CCA} ,V _{CCI} = 3.0 V, T _J = 70°C)
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		'-3'	Speed	'-2' 9	5peed	'-1' 9	5peed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL/PCI Out	put Module Timing									
t _{DLH}	Data-to-Pad LOW to HIGH		1.5		1.7		2.0		2.3	ns
t _{DHL}	Data-to-Pad HIGH to LOW		1.9		2.2		2.4		2.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.3		2.6		3.0		3.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		1.5		1.7		1.9		2.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.7		3.1		3.5		4.1	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns
PCI Output	Module Timing ³									
t _{DLH}	Data-to-Pad LOW to HIGH		1.8		2.0		2.3		2.7	ns
t _{DHL}	Data-to-Pad HIGH to LOW		1.7		2.0		2.2		2.6	ns
t _{ENZL}	Enable-to-Pad, Z to L		0.8		1.0		1.1		1.3	ns
t _{ENZH}	Enable-to-Pad, Z to H		1.2		1.2		1.5		1.8	ns
t _{ENLZ}	Enable-to-Pad, L to Z		1.0		1.1		1.3		1.5	ns
t _{ENHZ}	Enable-to-Pad, H to Z		1.1		1.3		1.5		1.7	ns
TTL Output	Module Timing									
t _{DLH}	Data-to-Pad LOW to HIGH		2.1		2.5		2.8		3.3	ns
t _{DHL}	Data-to-Pad HIGH to LOW		2.0		2.3		2.6		3.1	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.5		2.9		3.2		3.8	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.0		3.5		3.9		4.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.3		2.7		3.1		3.6	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Delays based on 10 pF loading.

Table 1-20 • A54SX32 Timing Characteristics (Continued)

(Worst-Case Commercial Conditions, V_{CCR}= 4.75 V, V_{CCA}, V_{CCI} = 3.0 V, T_J = 70°C)

		'-3' \$	Speed	'-2' !	5peed	'-1' \$	Speed	'Std'	Speed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Network									
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)		1.9		2.1		2.4		2.8	ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)		1.9		2.1		2.4		2.8	ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew		0.3		0.4		0.4		0.5	ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Arra	ay Clock Networks									
t _{rckh}	Input LOW to HIGH (light load) (pad to R-Cell input)		2.4		2.7		3.0		3.5	ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)		2.4		2.7		3.1		3.6	ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)		2.7		3.0		3.5		4.1	ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)		2.7		3.1		3.6		4.2	ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)		2.7		3.1		3.5		4.1	ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)		2.8		3.2		3.6		4.3	ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)		0.85		0.98		1.1		1.3	ns
t _{RCKSW}	Maximum Skew (50% load)		1.23		1.4		1.6		1.9	ns
t _{RCKSW}	Maximum Skew (100% load)		1.30		1.5		1.7		2.0	ns
TTL Output	Module Timing ³									
t _{DLH}	Data-to-Pad LOW to HIGH		1.6		1.9		2.1		2.5	ns
t _{DHL}	Data-to-Pad HIGH to LOW		1.6		1.9		2.1		2.5	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.8		3.2	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.1		3.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z		1.4		1.7		1.9		2.2	ns
t _{enhz}	Enable-to-Pad, H to Z		1.3		1.5		1.7		2.0	ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

3. Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.



Package Pin Assignments

84-Pin PLCC

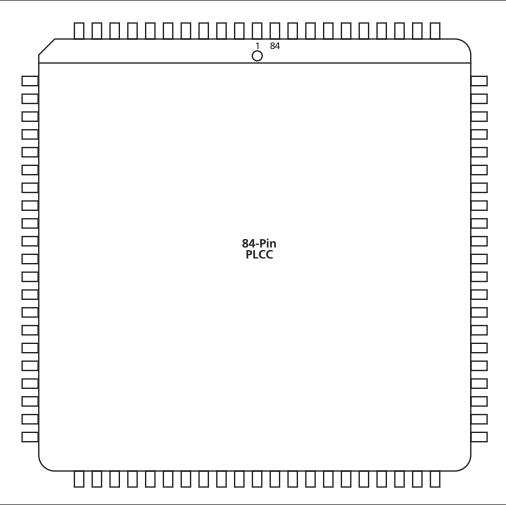


Figure 2-1 • 84-Pin PLCC (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.



	144-Pi	n TQFP		144-Pin TQFP						
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function	Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function			
73	GND	GND	GND	109	GND	GND	GND			
74	I/O	I/O	I/O	110	I/O	I/O	I/O			
75	I/O	I/O	I/O	111	I/O	I/O	I/O			
76	I/O	I/O	I/O	112	I/O	I/O	I/O			
77	I/O	I/O	I/O	113	I/O	I/O	I/O			
78	I/O	I/O	I/O	114	I/O	I/O	I/O			
79	V _{CCA}	V _{CCA}	V _{CCA}	115	V _{CCI}	V _{CCI}	V _{CCI}			
80	V _{CCI}	V _{CCI}	V _{CCI}	116	I/O	I/O	I/O			
81	GND	GND	GND	117	I/O	I/O	I/O			
82	I/O	I/O	I/O	118	I/O	I/O	I/O			
83	I/O	I/O	I/O	119	I/O	I/O	I/O			
84	I/O	I/O	I/O	120	I/O	I/O	I/O			
85	I/O	I/O	I/O	121	I/O	I/O	I/O			
86	I/O	I/O	I/O	122	I/O	I/O	I/O			
87	I/O	I/O	I/O	123	I/O	I/O	I/O			
88	I/O	I/O	I/O	124	I/O	I/O	I/O			
89	V _{CCA}	V _{CCA}	V _{CCA}	125	CLKA	CLKA	CLKA			
90	V _{CCR}	V _{CCR}	V _{CCR}	126	CLKB	CLKB	CLKB			
91	I/O	I/O	I/O	127	V _{CCR}	V _{CCR}	V _{CCR}			
92	I/O	I/O	I/O	128	GND	GND	GND			
93	I/O	I/O	I/O	129	V _{CCA}	V _{CCA}	V _{CCA}			
94	I/O	I/O	I/O	130	I/O	I/O	I/O			
95	I/O	I/O	I/O	131	PRA, I/O	PRA, I/O	PRA, I/O			
96	I/O	I/O	I/O	132	I/O	I/O	I/O			
97	I/O	I/O	I/O	133	I/O	I/O	I/O			
98	V _{CCA}	V _{CCA}	V _{CCA}	134	I/O	I/O	I/O			
99	GND	GND	GND	135	I/O	I/O	I/O			
100	I/O	I/O	I/O	136	I/O	I/O	I/O			
101	GND	GND	GND	137	I/O	I/O	I/O			
102	V _{CCI}	V _{CCI}	V _{CCI}	138	I/O	I/O	I/O			
103	I/O	I/O	I/O	139	I/O	I/O	I/O			
104	I/O	I/O	I/O	140	V _{CCI}	V _{CCI}	V _{CCI}			
105	I/O	I/O	I/O	141	I/O	I/O	I/O			
106	I/O	I/O	I/O	142	I/O	I/O	I/O			
107	I/O	I/O	I/O	143	I/O	I/O	I/O			
108	I/O	I/O	I/O	144	TCK, I/O	TCK, I/O	TCK, I/O			

	100-Pin VQF	P
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
1	GND	GND
2	TDI, I/O	TDI, I/O
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	TMS	TMS
8	V _{CCI}	V _{CCI}
9	GND	GND
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	V _{CCI}	V _{CCI}
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	I/O	I/O
34	PRB, I/O	PRB, I/O

	100-Pin VQF	P
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
35	V _{CCA}	V _{CCA}
36	GND	GND
37	V _{CCR}	V _{CCR}
38	I/O	I/O
39	HCLK	HCLK
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	V _{CCI}	V _{CCI}
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	TDO, I/O	TDO, I/O
50	I/O	I/O
51	GND	GND
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	I/O	I/O
56	I/O	I/O
57	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	V _{CCA}	V _{CCA}
68	GND	GND

	100-Pin VQF	P
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
69	GND	GND
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	V _{CCI}	V _{CCI}
83	I/O	I/O
84	I/O	I/O
85	I/O	I/O
86	I/O	I/O
87	CLKA	CLKA
88	CLKB	CLKB
89	V _{CCR}	V _{CCR}
90	V _{CCA}	V _{CCA}
91	GND	GND
92	PRA, I/O	PRA, I/O
93	I/O	I/O
94	I/O	I/O
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	TCK, I/O	TCK, I/O

Actel

54SX Family FPGAs

313-Pin PBGA

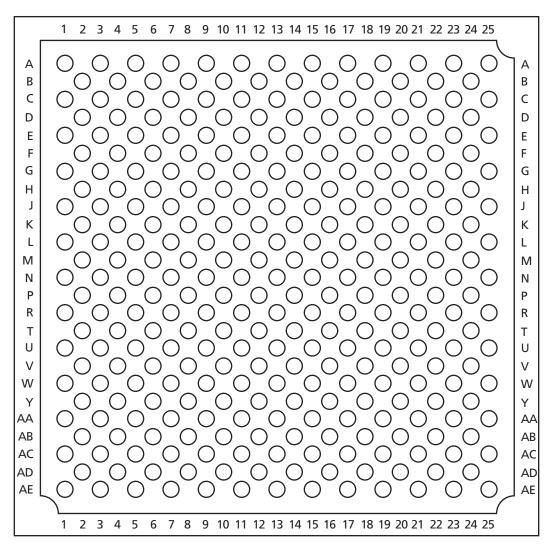


Figure 2-6 • 313-Pin PBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

329-Pin PBGA		329-Pin PBGA		329-Pi	n PBGA	329-Pin PBGA		
Pin Number	A54SX32 Function	Pin Number			A54SX32 Function	Pin Number	A54SX32 Function	
A1	GND	AA13	I/O	AC2	V _{CCI}	B14	I/O	
A2	GND	AA14	I/O	AC3	NC	B15	I/O	
A3	V _{CCI}	AA15	I/O	AC4	I/O	B16	I/O	
A4	NC	AA16	I/O	AC5	I/O	B17	I/O	
A5	I/O	AA17	I/O	AC6	I/O	B18	I/O	
A6	I/O	AA18	I/O	AC7	I/O	B19	I/O	
A7	V _{CCI}	AA19	I/O	AC8	I/O	B20	I/O	
A8	NC	AA20	TDO, I/O	AC9	V _{CCI}	B21	I/O	
A9	I/O	AA21	V _{CCI}	AC10	I/O	B22	GND	
A10	I/O	AA22	I/O	AC11	I/O	B23	V _{CCI}	
A11	I/O	AA23	V _{CCI}	AC12	I/O	C1	NC	
A12	I/O	AB1	I/O	AC13	I/O	C2	TDI, I/O	
A13	CLKB	AB2	GND	AC14	I/O	C3	GND	
A14	I/O	AB3	I/O	AC15	NC	C4	I/O	
A15	I/O	AB4	I/O	AC16	I/O	C5	I/O	
A16	I/O	AB5	I/O	AC17	I/O	C6	I/O	
A17	I/O	AB6	I/O	AC18	I/O	С7	I/O	
A18	I/O	AB7	I/O	AC19	I/O	C8	I/O	
A19	I/O	AB8	I/O	AC20	I/O	С9	I/O	
A20	I/O	AB9	I/O	AC21	NC	C10	I/O	
A21	NC	AB10	I/O	AC22	V _{CCI}	C11	I/O	
A22	V _{CCI}	AB11	PRB, I/O	AC23	GND	C12	I/O	
A23	GND	AB12	I/O	B1	V _{CCI}	C13	I/O	
AA1	V _{CCI}	AB13	HCLK	B2	GND	C14	I/O	
AA2	I/O	AB14	I/O	B3	I/O	C15	I/O	
AA3	GND	AB15	I/O	B4	I/O	C16	I/O	
AA4	I/O	AB16	I/O	B5	I/O	C17	I/O	
AA5	I/O	AB17	I/O	B6	I/O	C18	I/O	
AA6	I/O	AB18	I/O	В7	I/O	C19	I/O	
AA7	I/O	AB19	I/O	B8	I/O	C20	I/O	
AA8	I/O	AB20	I/O	В9	I/O	C21	V _{CCI}	
AA9	I/O	AB21	I/O	B10	I/O	C22	GND	
AA10	I/O	AB22	GND	B11	I/O	C23	NC	
AA11	I/O	AB23	I/O	B12	PRA, I/O	D1	I/O	
AA12	I/O	AC1	GND	B13	CLKA	D2	I/O	



144-Pin FBGA

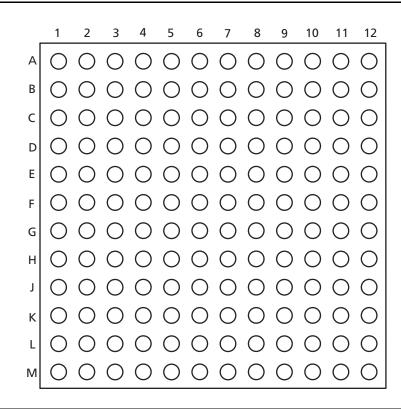


Figure 2-8 • 144-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

144-Pi	144-Pin FBGA		144-Pin FBGA		n FBGA	144-Pin FBGA		
Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	
A1	I/O	D1	I/O	G1	I/O	K1	I/O	
A2	I/O	D2	V _{CCI}	G2	GND	K2	I/O	
A3	I/O	D3	TDI, I/O	G3	I/O	К3	I/O	
A4	I/O	D4	I/O	G4	I/O	К4	I/O	
A5	V _{CCA}	D5	I/O	G5	GND	K5	I/O	
A6	GND	D6	I/O	G6	GND	К6	I/O	
A7	CLKA	D7	I/O	G7	GND	К7	GND	
A8	I/O	D8	I/O	G8	V _{CCI}	K8	I/O	
A9	I/O	D9	I/O	G9	I/O	К9	I/O	
A10	I/O	D10	I/O	G10	I/O	K10	GND	
A11	I/O	D11	I/O	G11	I/O	K11	I/O	
A12	I/O	D12	I/O	G12	I/O	K12	I/O	
B1	I/O	E1	I/O	H1	I/O	L1	GND	
B2	GND	E2	I/O	H2	I/O	L2	I/O	
B3	I/O	E3	I/O	H3	I/O	L3	I/O	
B4	I/O	E4	I/O	H4	I/O	L4	I/O	
B5	I/O	E5	TMS	H5	V _{CCA}	L5	I/O	
B6	I/O	E6	V _{CCI}	H6	V _{CCA}	L6	I/O	
B7	CLKB	E7	V _{CCI}	H7	V _{CCI}	L7	HCLK	
B8	I/O	E8	V _{CCI}	H8	V _{CCI}	L8	I/O	
B9	I/O	E9	V _{CCA}	H9	V _{CCA}	L9	I/O	
B10	I/O	E10	I/O	H10	I/O	L10	I/O	
B11	GND	E11	GND	H11	I/O	L11	I/O	
B12	I/O	E12	I/O	H12	V _{CCR}	L12	I/O	
C1	I/O	F1	I/O	J1	I/O	M1	I/O	
C2	I/O	F2	I/O	J2	I/O	M2	I/O	
C3	TCK, I/O	F3	V _{CCR}	J3	I/O	M3	I/O	
C4	I/O	F4	I/O	J4	I/O	M4	I/O	
C5	I/O	F5	GND	J5	I/O	M5	I/O	
C6	PRA, I/O	F6	GND	JG	PRB, I/O	M6	I/O	
C7	I/O	F7	GND	J7	I/O	M7	V _{CCA}	
C8	I/O	F8	V _{CCI}	J8	I/O	M8	I/O	
С9	I/O	F9	1/0	J9	I/O	M9	I/O	
C10	I/O	F10	GND	J10	I/O	M10	I/O	
C11	I/O	F11	I/O	J11	I/O	M11	TDO, I/O	
C12	I/O	F12	I/O	J12	V _{CCA}	M12	I/O	